

<b>Notice of References Cited</b>	Application/Control No. 10/580,822	Applicant(s)/Patent Under Reexamination BIGARRE ET AL.	
	Examiner Manuel L. Barbee	Art Unit 2857	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,395,242 A	07-1983	Liller et al.	445/5
*	B	US-6,338,790 B1	01-2002	Feldman et al.	205/777.5
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
*	U	Bigarre, J. et al.: "Trapping of Electrical Charges and Laser Damage", May 2003, Proceedings of the International Society for Optical Engineering. Volume 4932. pages 258-267.
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.